

se and ZnTe, it
odel.

Photovoltaic characteristics of a $ZnS_xSe_{1-x}/GaAs$ heterojunction with gradually changed x

Jifeng Wang^a and Xurong Xu^b

^a Changchun Institute of Physics, Chinese Academy of Sciences, Changchun 130021, PR China

^b Tianjin Technological Institute, Tianjin 300191, PR China

Heteroepitaxial layers of ZnS_xSe_{1-x} with gradually changed x are grown on GaAs substrates by means of VPE. ZnS and ZnSe powders are vaporized and the vapor is carried by a flow of H_2 gas. Their photovoltaic characteristics are studied. An open circuit voltage of 0.76 V and a short circuit current of 32.9 mA cm^{-2} are obtained. The highest efficiency for the solar cells of $ZnS_xSe_{1-x}/GaAs$ without antireflection coatings is 11%, 2% higher than that of $ZnSe/GaAs$ cells fabricated in our laboratory. This value is found to be strongly dependent on the annealing temperature of ZnS_xSe_{1-x} thin film.

Cliffs, 1962).

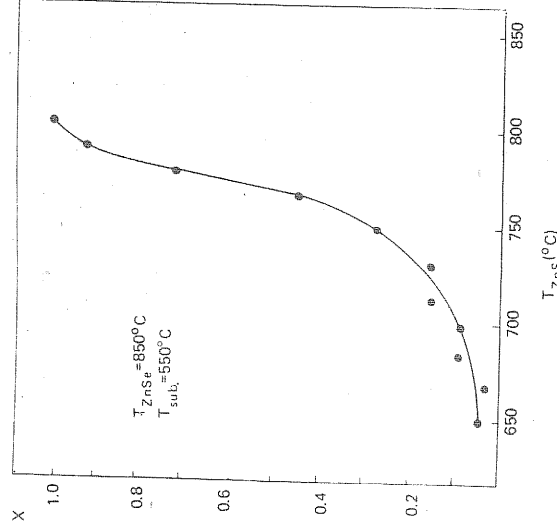
1. Introduction

Recently, increasing attention has been paid to the development of photoelectric conversion devices utilizing semiconductor heterojunctions. n-ZnSe/p-GaAs solar cells have been regarded as one of the promising candidates for achieving high efficiency as well as a flat photoresponse spectrum in the visible region. Sahai et al. [1] predicted that a n-ZnSe/p-GaAs heterojunction has the potential of surmounting GaAs and Si solar cells in efficiency. Gaugash et al. [2] described photovoltaic cells of ZnSe/GaAs on ZnSe substrates. The efficiency is about 8-9% under simulated solar conditions. In the ZnSe/GaAs cells, ZnSe was deposited by CVD onto GaAs substrates. The efficiency is reported to be 7% by Besomi [3]. Although the band gap of ZnSe ($E_g = 2.7 \text{ eV}$) is wide enough to transmit the whole visible effectively into narrow-gap GaAs ($E_g = 1.43 \text{ eV}$), there is still a "dead layer" in these cells. It is very significant to develop a cell with wider E_g for space technology in order to use the ultraviolet region of sun light. For this reason, we prepared $ZnS_xSe_{1-x}/GaAs$ heterojunction devices in which the x value is gradually varied from 0 to 1 on the basis of ZnSe/GaAs cell.

2. Experimental details

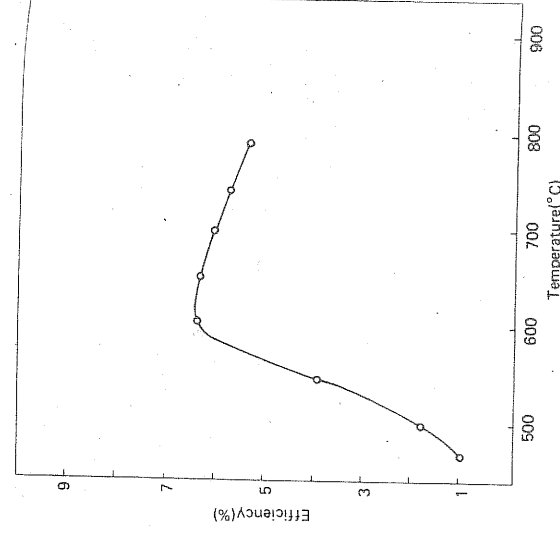
ZnSe source was synthesized from single substance Zn (99.99999%) and Se (99.9999%) under a H_2-O_2 flame. It was then purified twice. p-GaAs single crystals (Zn-doped, p: 10^{18} cm^{-3}) were used as substrates. Its orientation is (1 0 0) or 2° decline from (1 1 0). Before epitaxy, polished GaAs substrates were rinsed with $CICHCCl_3$, CH_3COCH_3 , C_2H_5OH and de-ionized water, etched with a solution of 3:1:1 $H_2SO_4:H_2O:H_2O_2$ at $50^\circ C$ for 1 min and treated in boiling HCl for 3 min. Then the substrates were thoroughly rinsed with de-ionized water and put into the reaction chamber. The substrates, and the ZnSe and ZnS sources were heated $100^\circ C$ for 12 h, at $300^\circ C$ for 1 h and at $620^\circ C$ for 5 min in order to remove the water and organic matters. Figure 1 shows the relation between x and T_{ZnS} (temperature of ZnS source). Table 1 gives the typical growth conditions for ZnS_xSe_{1-x} thin film on the substrates of GaAs.

As the resistivity of as-grown ZnS_xSe_{1-x} layers is as high as $10^5 \Omega cm$, the sufficient output current from the junction cannot be obtained. We reduced the sample resistivity by means of Zn saturated vapour at $600^\circ C$ for 15 h as stated in ref. [4]. This method is found to be more effective for the

Fig. 1. Relation between x value and T_{ZnS} .

ZnS_xSe_{1-x} thin layers. As GaAs substrates are doped with $Zn(10^{18} \text{ cm}^{-3})$, Zn-treatment for ZnS_xSe_{1-x} does not destroy the electrical properties of the junction [5]. A series of experiments for reducing resistivity have been done at different temperature and the dependence of efficiency on annealing temperature has been obtained (fig. 2).

On both sides of the samples In electrodes were formed by means of the annealing at 300°C in a N_2 atmosphere for 3 min. In order to compare these cells with those of ZnSe/GaAs, thin layers of ZnSe were grown onto GaAs substrates in the same way as in $ZnS_xSe_{1-x}/GaAs$.

Fig. 2. Efficiency of ZnS_xSe_{1-x} solar cells as a function of annealing temperature.

3. Results and discussion

Figure 3 is the X-ray diffraction pattern of $(4\ 0\ 0)$ for $ZnS_xSe_{1-x}/GaAs$. The diffractive angles for ZnSe, GaAs and ZnS are 66.12° , 66.25° and 69.70° , respectively. Figure 3 shows a continuous band from 66.081° to 69.699° as well as three sharp diffractive peaks ascribed to ZnSe, GaAs and ZnS. This means that x in thin films of ZnS_xSe_{1-x} is gradually changed from 0 to 1. The other experiments, such as the photoluminescence spectra, also lead to this conclusion.

Table 1
Growth conditions for $ZnS_xSe_{1-x}/GaAs$ ($x: 0-1$).

T_{ZnSe}	T_{ZnS}	T_{sub}	$J_{ZnSe}^H = J_{ZnS}^H$
Temperature range		Heating rate	
850°C	25°C-500°C	1.5°C/min	50 cm ³ /min
	500°C-650°C	0.5°C/min	
	650°C-800°C	0.25°C/min	

T_{ZnSe} : temperature of ZnSe source.

T_{ZnS} : temperature of ZnS source.

T_{sub} : temperature of GaAs substrates.

$J_{ZnSe}^H (J_{ZnS}^H)$: H_2 rate of flow for ZnSe(ZnS) source.

Fig. 3. X-ray c

Figure 4

excitation

100 mW cm

$ZnS_xSe_{1-x}/$

tage is 0.

$ZnS_xSe_{1-x}/$

18.5 mA cm

$ZnS_xSe_{1-x}/$

efficiency is

$ZnS_xSe_{1-x}/$

The effici

is 2% higher

is that the Zr

spectral resp

and this sola

However, usi

solar cells, t

although the

thought that

These defects

current is din

The relat

we reduced t

efficiency has

lower than 6

increasing ten

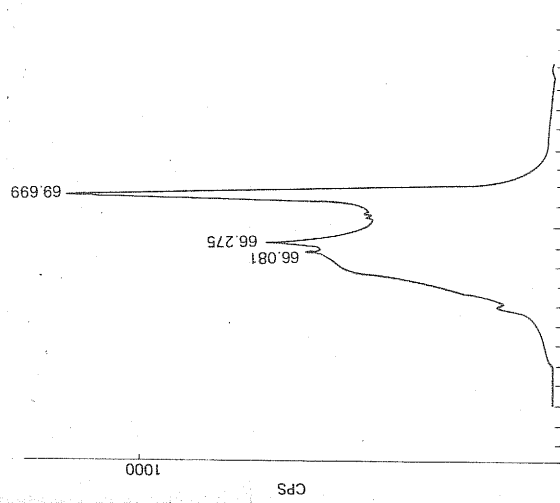


Fig. 3. X-ray diffraction pattern (4 0 0) $ZnS_xSe_{1-x}/GaAs$.

Figure 4 shows the $J-V$ load characteristics by simulated solar radiation of 100 mW cm^{-2} for $n\text{-ZnSe/p-GaAs}$ and $n\text{-ZnS}_x\text{Se}_{1-x}/\text{GaAs}$ ($x: 0-1$). The open circuit voltage is 0.86 V for $ZnSe/GaAs$, 0.76 V for $ZnS_xSe_{1-x}/GaAs$ and the short circuit current is 18.5 mA cm^{-2} for $ZnSe/GaAs$, 32.9 mA cm^{-2} for $ZnS_xSe_{1-x}/GaAs$. The corresponding conversion efficiency is 9% for $ZnSe/GaAs$, and 11% for $ZnS_xSe_{1-x}/GaAs$.

The efficiency of a $ZnS_xSe_{1-x}/GaAs$ solar cell is 2% higher than that of $ZnSe/GaAs$. The reason is that the $ZnS_xSe_{1-x}/GaAs$ solar cell has a better spectral response in the range from 1.43 to 3.6 eV and this solar cell shows almost no "dead layer". However, using $ZnSe/GaAs$ or $ZnS_xSe_{1-x}/GaAs$ solar cells, the short circuit current is very low although the open circuit voltage is high. It is thought that a lot of defects exist in the interface. These defects capture carriers and the short circuit current is diminished.

The relation between the temperature at which we reduced the sample resistivity and solar cells efficiency has been studied (fig. 2). At temperatures lower than 600°C , the efficiency increases with increasing temperature. This is because the V_{Zn} (Zn

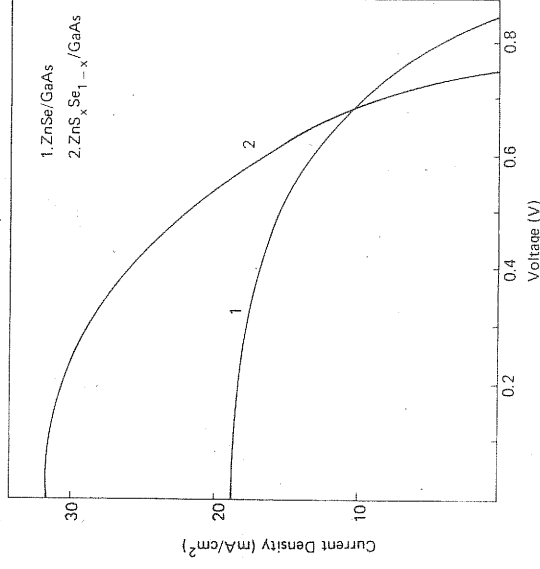


Fig. 4. $J-V$ characteristics and simulated solar radiation of 100 mW/cm^2 for $ZnSe/GaAs$ and $ZnS_xSe_{1-x}/GaAs$.

vacancy) concentration in epitaxial layers is reduced and the intrinsic concentration of donors is increased. At temperatures higher than 600°C , the efficiency decreases because the donor concentration is so high that there is a shrink of the forbidden band which leads to the diminishing of the short circuit current.

4. Summary

ZnS_xSe_{1-x} thin films with gradually changed x have been grown successfully on $GaAs$ substrates by VPE technique. A solar cell with 11% efficiency is obtained. At the same time, $ZnSe/GaAs$ solar cells with 9% efficiency are achieved. This value of efficiency is the highest for $ZnSe/GaAs$. Efforts are under way for improving short circuit current.

Acknowledgement

The authors would like to thank Professor Yibing Li and Professor Xiwu Fan for helpful assistance.

as a function of

on pattern of
he diffractive
 66.12° , 66.25°
shows a con-
 99° as well as
bed to $ZnSe$,
at x in thin
anged from 0
as the photo-
ad to this

References

- [1] R. Sahai and A.G. Milnes, *Solid State Electron.* 13 (1970) 1289.
- [2] P.V. Gaugash et al., *Sov. Phys. Semicond.* 9 (1976) 1239.
- [3] P. Besomi et al., *Thin Solid Films* 87 (1982) 113.
- [4] M. Aven and H.H. Woodury, *Appl. Phys. Lett.* 1 (1962) 53.
- [5] J. Aranovich et al., *J. Appl. Phys.* 49 (1978) 2584.

Zee

R. He

Institut

ZnO

structure
tempera
substitu
ε-mode;
term an
resonan

ZnO is re
cence in th
exhibits aro
tured lumine
cence is kno
has been ti
including fin
tion measure
mental effort
to develop a
cerning the r
transition. T
defects have l

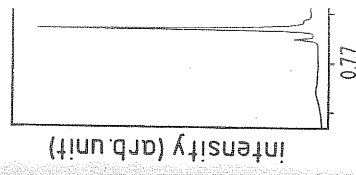


Fig. 1. Unpolarized Raman scattering intensity of ZnO, the inset shows the

0022-2313/91/\$0